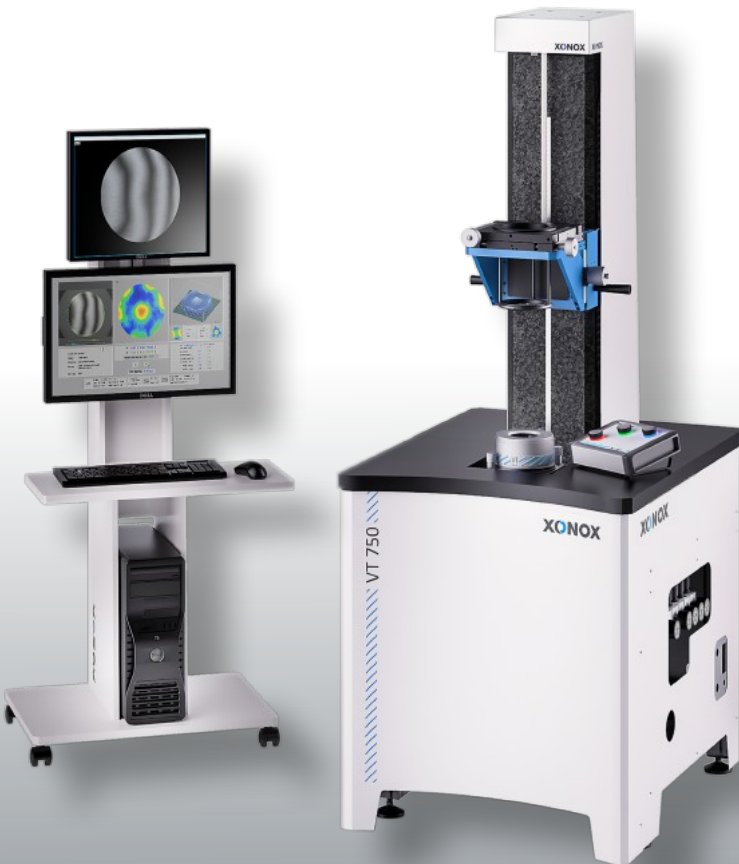


# VT 750

## VERTICAL INTERFEROMETER SYSTEM

- \_precision interferometer tower for production-, quality inspection- and metrology lab environments
- \_natural granite column with extremely flat and precise guiding surfaces provide for ease of use and very accurate measurement of radius of curvature on optical components
- \_highly precise and accurate linear scale with exceptional resolution, directly interfaced to fringe analysis software
- \_measurement table is balanced and guided on air bearing slide for quick, easy and accurate setup and movement
- \_small foot print and exceptional value combined with high accuracy and and rigid, maintenance free design
- \_robust vibration damping system, perfect for use in industrial production environments
- \_XONOX **X-fiz 100** (4") or **X-fiz 130** (5.2") high performance Fizeau interferometer with electronic control of optical zoom (1x to 10x), focus and contrast
- \_innovative, powerful and user friendly fringe analysis system **X-fringe2** with different smart and intelligent modes to suit various applications
- \_choose from low cost „ST“ version with static fringe analysis up to high performance „PS2“ phase shifting version
- \_system can be equipped either with PC table, 2 screens, mouse and keyboard or with built-in PC and touch panel for optimized operation and minimized space requirement in production environment
- \_additionally available in a "tower only" version „B“ for integrating existing or 3rd party interferometer units or version „Z“ equipped with ZYGO Verifire and ZYGO MX fringe analysis software



<b>WORKING RANGE</b>	min. 750mm travel (800mm linear scale range), up to 200mm test diameter (depending on used TS and part holder) + micrometer fine adjustment for easy and precise setting of catseye and confocal position
<b>VERSIONS</b>	<ul style="list-style-type: none"> <li>_ <b>VT750 ST</b> with XONOX <b>X-fiz 100</b> (4") / <b>X-fiz 130</b> (5.2") with <b>10x</b> optical zoom and static fringe analysis system XONOX „<b>X-fringe ST</b>“</li> <li>_ <b>VT750 PS2</b> with XONOX <b>X-fiz 100</b> (4") / <b>X-fiz 130</b> (5.2") with <b>10x</b> optical zoom, phase shifting fringe analysis system XONOX „<b>X-fringe2</b>“ and piezo phase shifter XONOX „<b>X-phase PMR</b>“</li> <li>_ <b>VT750 Z</b> with ZYGO Verifire 4" or 6" interferometer unit and ZYGO Mx phase shifting fringe analysis</li> <li>_ <b>VT750 B</b> „tower only“ version for integrating existing interferometer units. Optionally with XONOX fringe analysis system X-fringe ST or X-fringe PS with X-phase PMR phase shifter.</li> </ul>
<b>MEASURING SYSTEM</b>	incremental high precision linear measuring system with PC interface and temperature expansion compensation function (standard) / alternatively laser distance measuring system (option)
<b>MEASURING ACCURACY</b>	linear scale: up to +/- 0.7µm per 500mm @ 20°C, up to 0.1 µm resolution (standard 0.5µm)
<b>DIMENSIONS (WxDxH) / WEIGHT</b>	800 x 900 x 2100 mm when using touch screen for fringe analysis (additional space required if PC is used for fringe analysis, XONOX PC-table optionally available) / approx. 500kg
<b>CONNECTIONS</b>	110-240 V / 50-60 Hz, compressed air: 6 bar
<b>COLOR</b>	Light grey RAL 7035

Specifications subject to change without notice

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